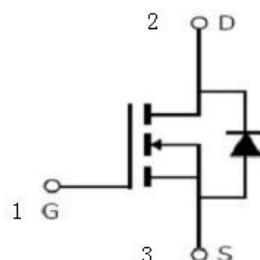
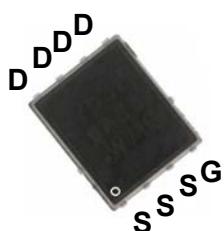


General Description

These N-Channel enhancement mode power field effect transistors are using SGT technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

Features

V_{DS}	60V
I_D (at $V_{GS}=10V$)	95A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	4.0mΩ(Typ)

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Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	I_D	95	A
	I_D	60	A
Maximum Power Dissipation	P_D	75	W
Drain Current – Pulsed	I_{DM}	360	A
Single pulse avalanche energy	E_{AS}	160	mJ
Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Unit
Thermal Resistance junction-case	$R_{\theta JC}$		1.1	°C /W
Thermal Resistance junction-to-Ambient	$R_{\theta JA}$		62	°C /W

Electrical Characteristics (TJ=25°C unless otherwise noted)

Symbol	Parameter	Condition	Min	Typ	Max	Unit
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	60			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=60V, V_{GS}=0V$			1	μA
I_{GSS}	Gate-Body Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$			± 100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	1.2	1.8	2.5	V
$R_{DS(ON)}$	Drain-Source On-State Resistance	$V_{GS}=10V, I_D=20A$		4.0	5.0	$m\Omega$
		$V_{GS}=4.5V, I_D=15A$		5.2	6.5	$m\Omega$
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{DS}=30V, V_{GS}=0V, F=1.0MHz$		2030		pF
C_{oss}	Output Capacitance			430		pF
C_{rss}	Reverse Transfer Capacitance			4.5		pF
SWITCHING PARAMETERS						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD}=30V, I_D=5A, V_{GS}=10V, R_G=6\Omega$		6.3		nS
t_r	Turn-on Rise Time			8		nS
$t_{d(off)}$	Turn-Off Delay Time			39		nS
t_f	Turn-Off Fall Time			15		nS
Q_g	Total Gate Charge	$V_{DS}=30V, I_D=5A, V_{GS}=10V$		32		nC
Q_{gs}	Gate-Source Charge			4		nC
Q_{gd}	Gate-Drain Charge			5		nC
V_{SD}	Diode Forward Voltage	$V_{GS}=0V, I_{SD}=1A$		0.72	1.3	V
R_g	Gate resistance	$V_{GS}=0V, V_{DS}=0V, F=1MHz$		1		Ω

Note:

- Repetitive Rating : Pulsed width limited by maximum junction temperature.
- $V_{DD}=25V, L=0.1mH, I_{AS}=42A$, Starting $TJ=25^\circ C$
- The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.
- Essentially independent of operating temperature.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

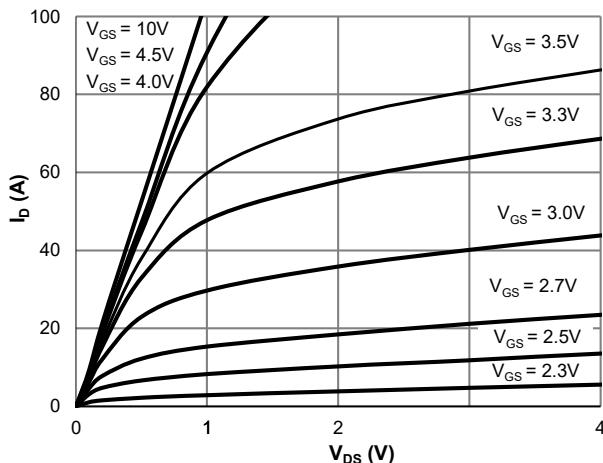


Figure 1: Saturation Characteristics

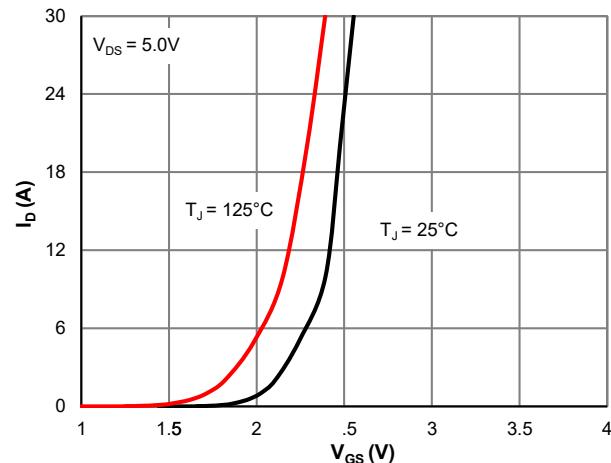


Figure 2: Transfer Characteristics

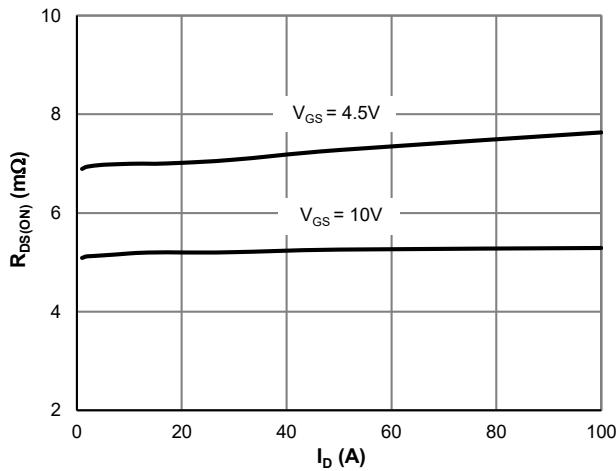
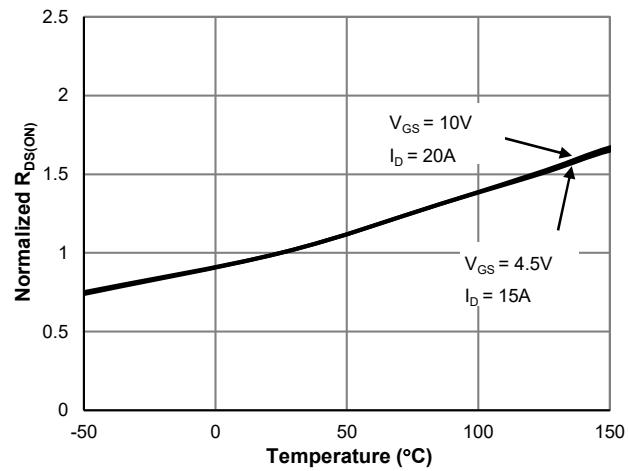
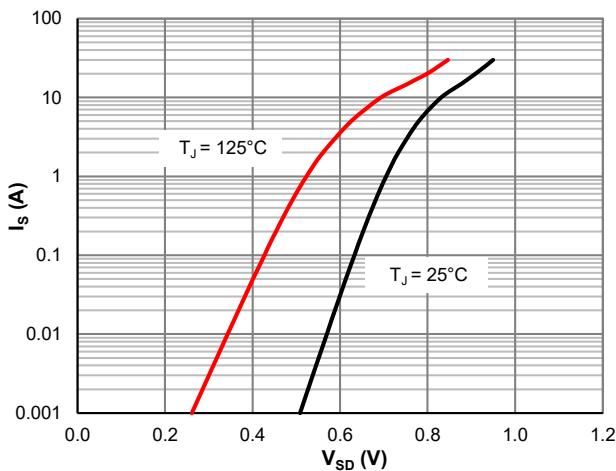
Figure 3: $R_{DS(ON)}$ vs. Drain CurrentFigure 4: $R_{DS(ON)}$ vs. Junction Temperature

Figure 5: Body-Diode Characteristics

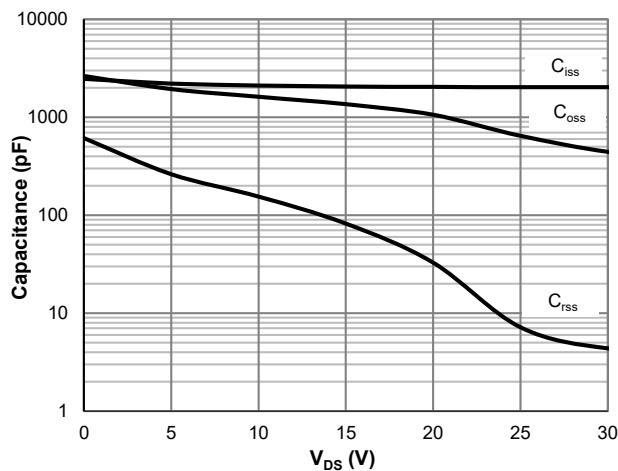


Figure 6: Capacitance Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

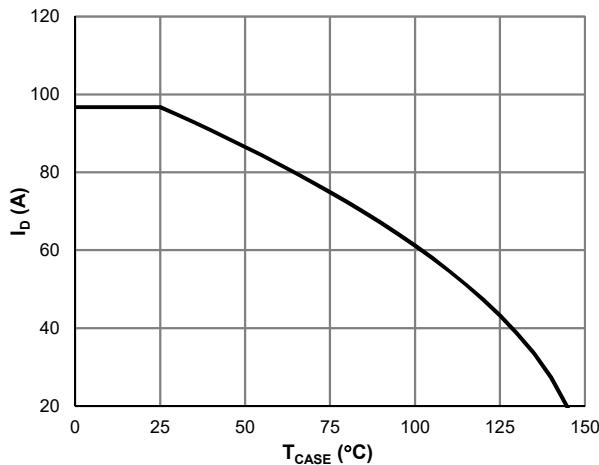


Figure 7: Current De-rating

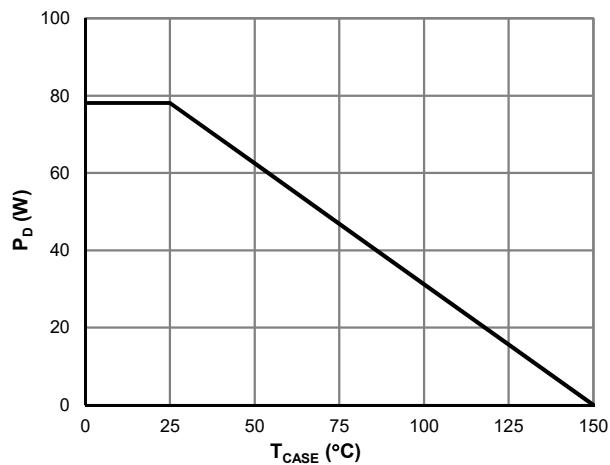


Figure 8: Power De-rating

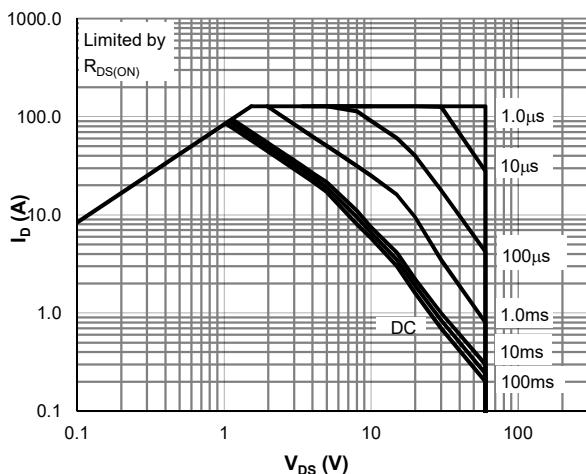


Figure 9: Maximum Safe Operating Area

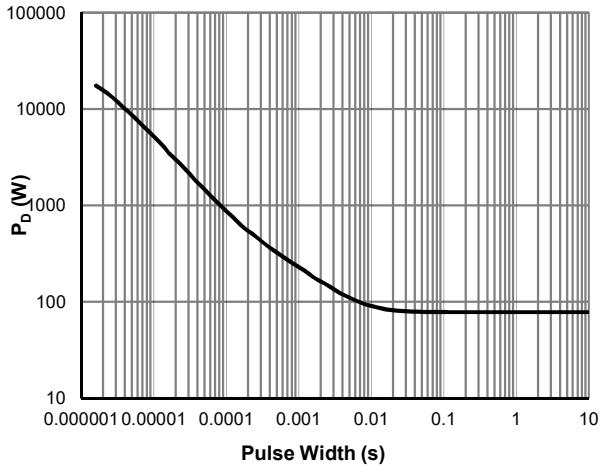


Figure 10: Single Pulse Power Rating, Junction-to-Case

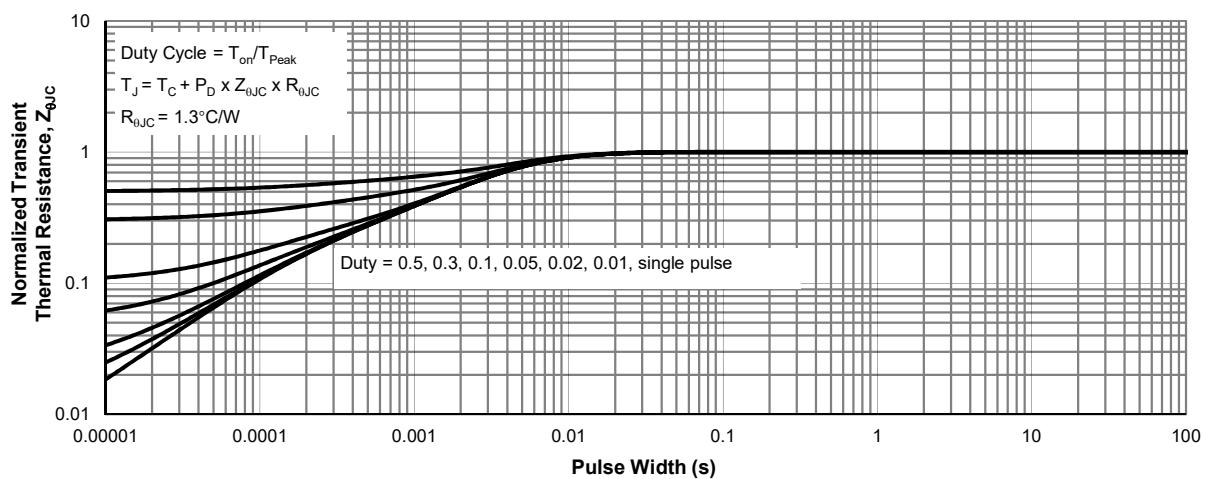
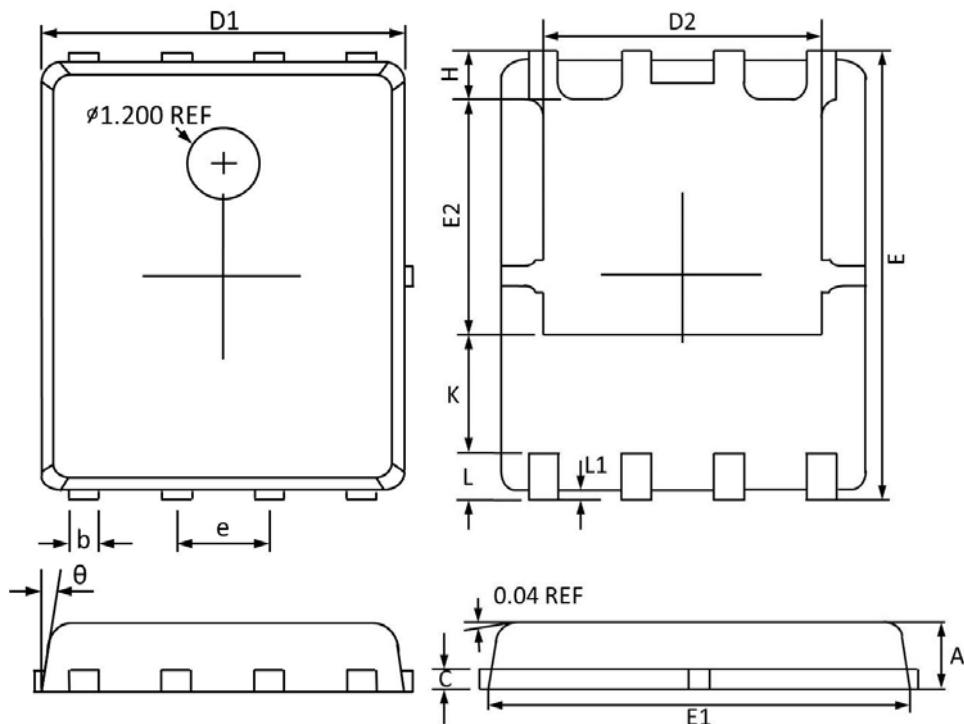


Figure 11: Normalized Maximum Transient Thermal Impedance

PDFN5*6 PACKAGE INFORMATION



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	MAX	MIN	MAX	MIN
A	1.100	0.800	0.043	0.031
b	0.510	0.330	0.020	0.013
C	0.300	0.200	0.012	0.008
D1	5.100	4.800	0.201	0.189
D2	4.100	3.610	0.161	0.142
E	6.200	5.900	0.244	0.232
E1	5.900	5.700	0.232	0.224
E2	3.780	3.350	0.149	0.132
e	1.27BSC		0.05BSC	
H	0.700	0.410	0.028	0.016
K	1.500	1.100	0.059	0.043
L	0.710	0.510	0.028	0.020
L1	0.200	0.060	0.008	0.002
θ	12°	0°	12°	0°